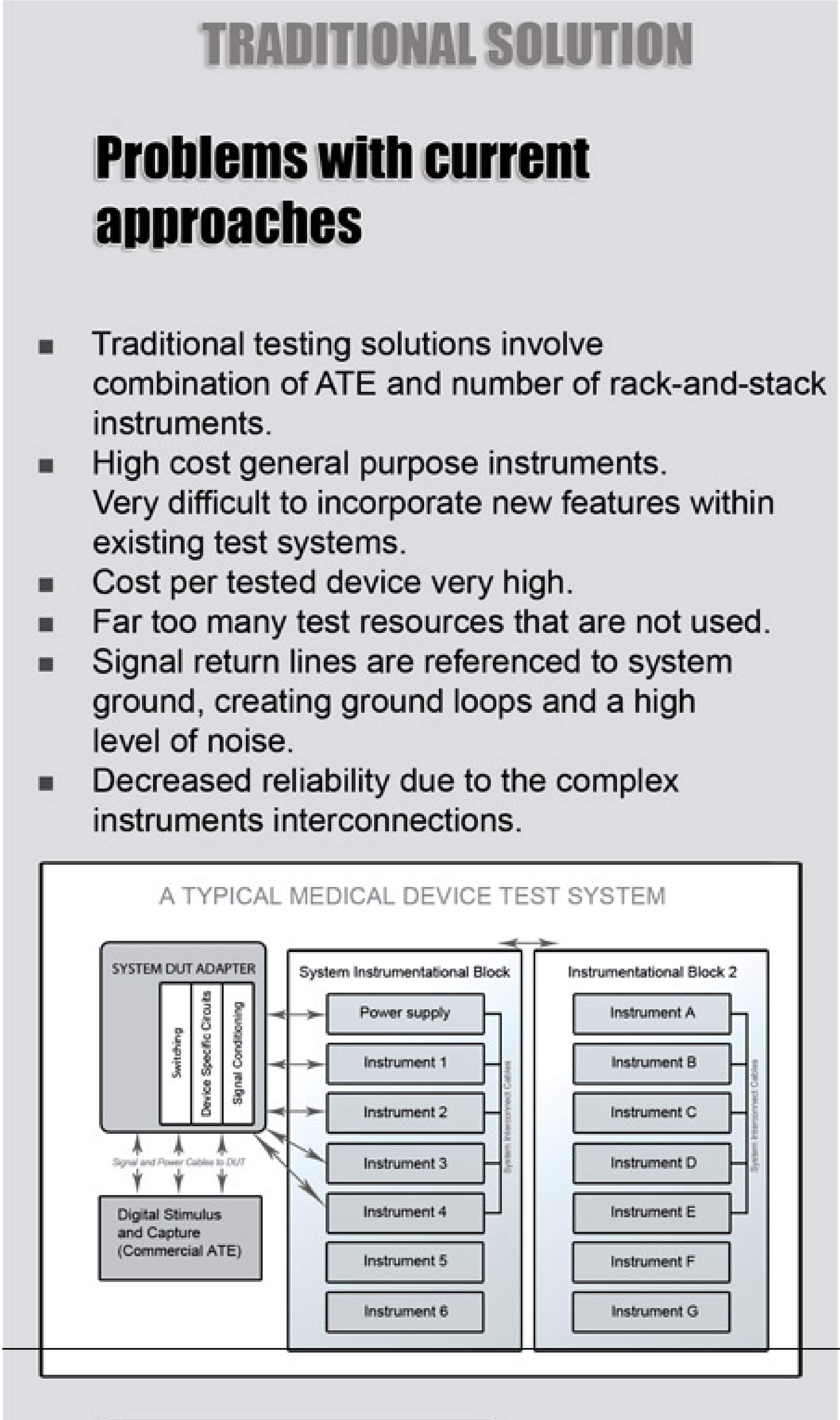

TRADITIONAL SOLUTION

Problems with current approaches

- Traditional testing solutions involve combination of ATE and number of rack-and-stack instruments.
- High cost general purpose instruments.
  Very difficult to incorporate new features within existing test systems.
- Cost per tested device very high.
- Far too many test resources that are not used.
- Signal return lines are referenced to system ground, creating ground loops and a high level of noise.
- Decreased reliability due to the complex instruments interconnections.